

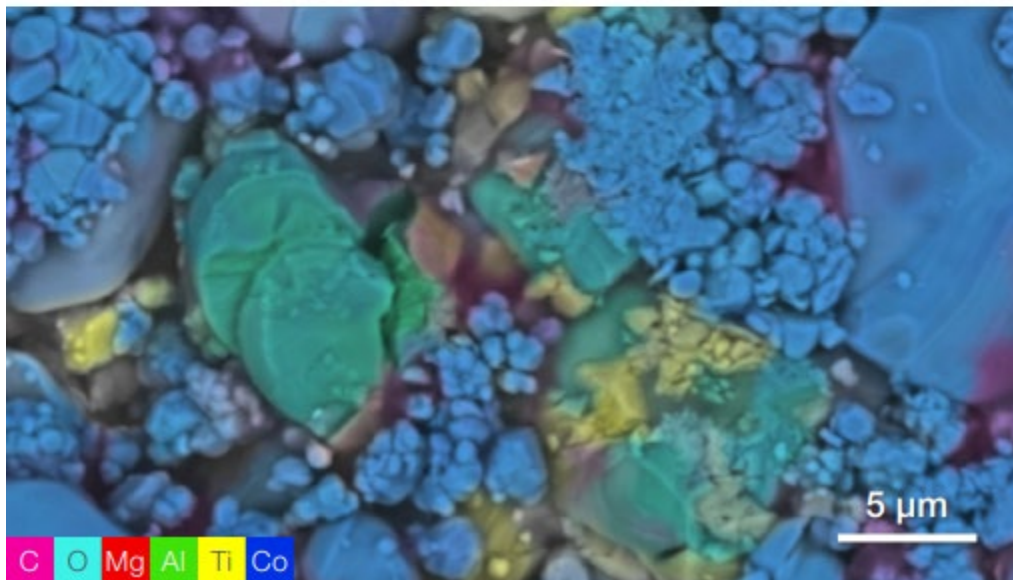
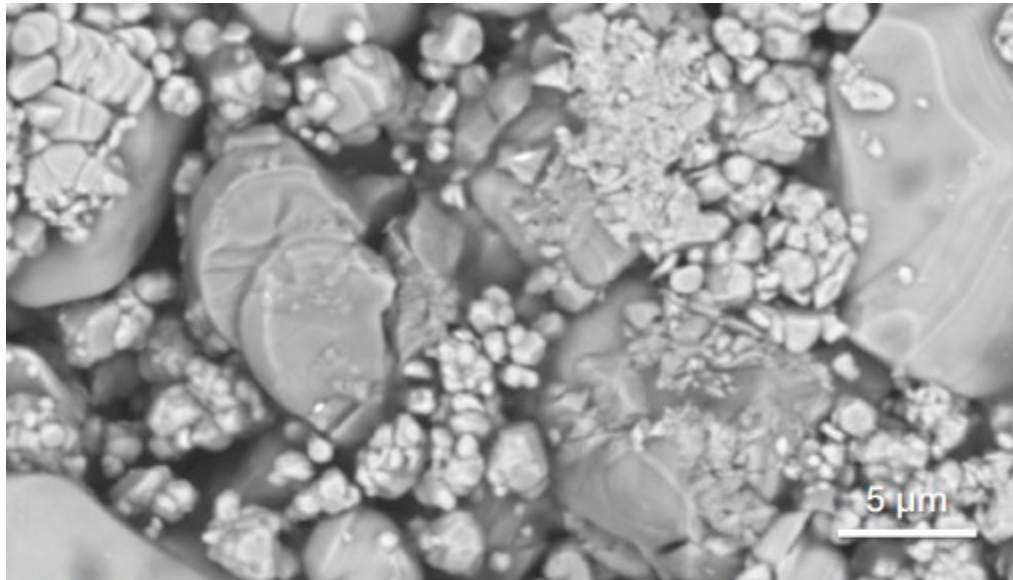
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## Using SEM/EDS for rapid and accurate failure analysis.

Mr. Tom Warwick

BlueScientific Ltd, Cambridge, United Kingdom

### Abstract



learn how you can focus your time and effort on quickly and easily combining imaging and compositional analysis of your samples instead of focusing on how to use the instrument.

Failure can occur at any stage of a component's production for a wide variety of reasons. Determination of the root cause is essential. High accuracy and short time to results are critical when characterizing a large amount of samples. Scanning electron microscopy (SEM) combined with energy dispersive X-ray spectroscopy (EDS) is a strong solution for both morphological analysis and chemical characterization.

In this webinar, you will see the latest Thermo Scientific™ technologies applied to the failure analysis of unique automotive, ceramics, steel, and plastic samples, demonstrating the speed and simplicity you can expect.